

US00D409929S

United States Patent [19]
Fisher et al.

[11] **Patent Number: Des. 409,929**
[45] **Date of Patent: ** May 18, 1999**

[54] **ELECTRICAL TEST PROBE**

OTHER PUBLICATIONS

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1994 Fluke Test & Measurement Catalog, Fluke Corporation, 1993 Everett, Washington.

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[73] Assignee: **Fluke Corporation**, Everett, Wash.

[57] **CLAIM**

[**] Term: **14 Years**

The ornamental design for an electrical test probe, as shown.

[21] Appl. No.: **29/078,921**

DESCRIPTION

[22] Filed: **Nov. 6, 1997**

FIG. 1 is a top, front, and right side perspective view of an electrical test probe showing our new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a right side elevational view thereof;
FIG. 4 is a back elevational view thereof;
FIG. 5 is a top plan view thereof; and,
FIG. 6 a bottom plan view thereof.

[51] **LOC (6) Cl.** **10-04**

[52] **U.S. Cl.** **D10/78**

[58] **Field of Search** D10/78; 324/72.5, 324/149, 156, 508, 509, 538; 340/815.74

The broken line showing is for illustrative purposes only and forms no part of the claimed design.

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 391,503 3/1998 Van Dyk D10/78

1 Claim, 1 Drawing Sheet



FIG. 1

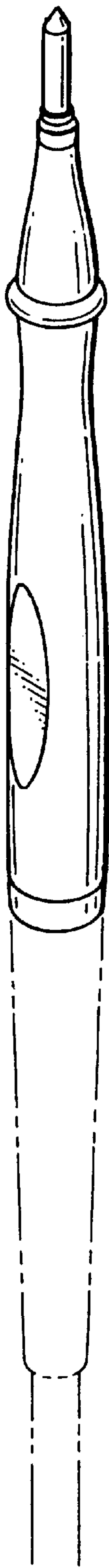


FIG. 2

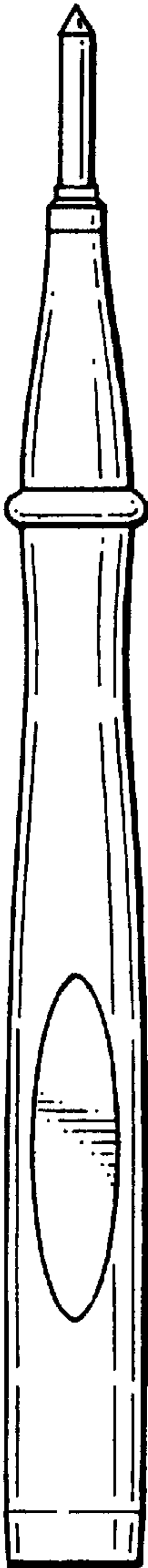


FIG. 3

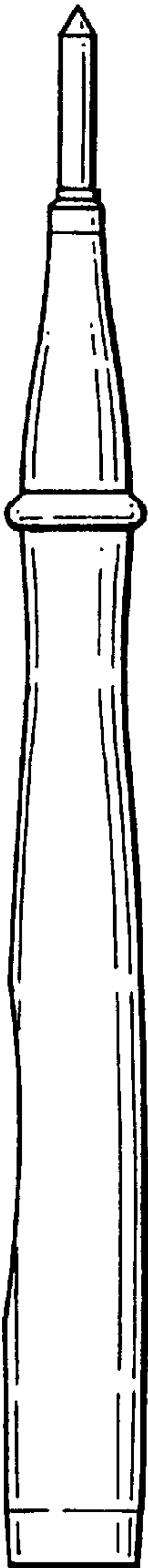


FIG. 4

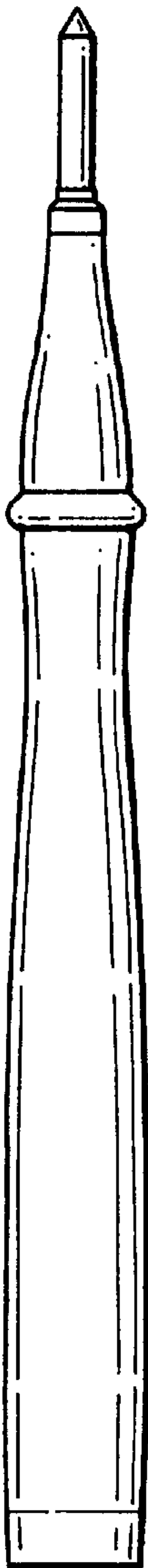


FIG. 5



FIG. 6

